

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	4	("20040100246") or ("5796751").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/07/11 09:07
S2	1	de-19845409-\$.did.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/11 09:09
S3	2	ep-994361-\$.did.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/11 09:08
S4	386	(324/76.82.ccls.) and @ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 09:19
S5	1361	(324/76.77,76.11.ccls.) and @ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 10:21
S6	2	S4 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7 record\$5 meter\$5) same (parameter near3 (IC (integrated adj circuit) \$6chip ASIC))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/11 09:42
S7	1	S5 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7 record\$5 meter\$5) same (parameter near3 (IC (integrated adj circuit) \$6chip ASIC))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/11 09:59

S8	2894	(check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7 record\$5 meter\$5) same (parameter near3 (IC (integrated adj circuit) \$6chip ASIC))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/11 13:20
S9	2503	S8 and @ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/11 09:58
S10	21	S9 and counter same ((state mode status) near3 (IC (integrated adj circuit) \$6chip ASIC))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 10:07
S11	42	S9 and (external near2 connect\$5) near3 (IC (integrated adj circuit) \$6chip ASIC)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/11 13:25
S12	2503	(check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7 record\$5 meter\$5) same (parameter near3 (IC (integrated adj circuit) \$6chip ASIC)) and @ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/11 14:27
S13	122	S12 and ((check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7 record\$5 meter\$5) near3 voltage near3 (change variation difference))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 09:13
S14	3	S13 and (external near2 connect\$5) near3 (IC (integrated adj circuit) \$6chip ASIC)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/11 13:58
S15	7	S13 and (anal\$5 adj2 (assembly unit system device apparatus machine mechanism section station means module set instrument tool circuit equipment cell)) near3 (IC (integrated adj circuit) \$6chip ASIC)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/11 13:33

S16	12	S13 and (anal\$5 adj2 (assembly unit system device apparatus machine mechanism section station means module set instrument tool circuit equipment cell)) near5 (IC (integrated adj circuit) \$6chip ASIC)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/11 13:46
S17	3	(anal\$5 adj2 (assembly unit system device apparatus machine mechanism section station means module set instrument tool circuit equipment cell)) near5 (IC (integrated adj circuit) \$6chip ASIC) near3 (external near2 connect\$5) and @ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/11 13:53
S18	3240	((analysis analyzing analyzed analysing) adj2 (assembly unit system device apparatus machine mechanism section station means module set instrument tool circuit equipment cell)) analyzer analyser) near5 (IC (integrated adj circuit) \$6chip ASIC) and @ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/11 16:09
S19	39	S18 and (external near2 connect\$5) near3 (IC (integrated adj circuit) \$6chip ASIC)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/11 13:59
S20	2360	((analysis analyzing analyzed analysing) adj2 (assembly unit system device apparatus machine mechanism section station means module set instrument tool circuit equipment cell)) analyzer analyser) near3 (IC (integrated adj circuit) \$6chip ASIC) and @ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/11 13:58
S21	24	S20 and (external near2 connect\$5) near3 (IC (integrated adj circuit) \$6chip ASIC)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/11 13:59
S22	7	(check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7 record\$5 meter\$5) same (parameter near3 (IC (integrated adj circuit) \$6chip ASIC)) and S19	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/11 14:18
S23	1110	(check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7 record\$5 meter\$5) near3 (parameter near3 (IC (integrated adj circuit) \$6chip ASIC)) and @ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/11 14:39

S24	49	S23 and (((analysis analyzing analyzed analysing) adj2 (assembly unit system device apparatus machine mechanism section station means module set instrument tool circuit equipment cell)) analyzer analyser) near5 (IC (integrated adj circuit) \$6chip ASIC)	OR	ON	2005/07/12 09:13
S25	1111	(check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7 record\$5 meter\$5) near3 (parameter near3 (IC (integrated adj circuit) \$6chip ASIC)) and @ad<"20030810"	OR	ON	2005/07/12 14:24
S26	49	S25 and (((analysis analyzing analyzed analysing) adj2 (assembly unit system device apparatus machine mechanism section station means module set instrument tool circuit equipment cell)) analyzer analyser) near5 (IC (integrated adj circuit) \$6chip ASIC)	OR	ON	2005/07/12 09:16
S27	3	S26 and ((check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7 record\$5 meter\$5) near3 voltage near3 (change variation difference))	OR	ON	2005/07/12 09:14
S28	9	(((analysis analyzing analyzed analysing) adj2 (assembly unit system device apparatus machine mechanism section station means module set instrument tool circuit equipment cell)) analyzer analyser) near5 (IC (integrated adj circuit) \$6chip ASIC) same (((check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7 record\$5 meter\$5) near3 voltage near3 (change variation difference))))	OR	ON	2005/07/12 10:12
S29	8	S28 and @ad<"20030810"	OR	ON	2005/07/12 09:42
S30	70	S25 and counter same (state mode status)	OR	ON	2005/07/12 09:34

S31	0	S30 and counter same (digital\$3 near3 cod\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 09:35
S32	0	S25 and counter same (digital\$3 near3 cod\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 09:45
S33	4	S25 and (parameter near3 (IC (integrated adj circuit) \$6chip ASIC)) same (digital\$3 near3 cod\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 09:49
S34	1	counter same (parameter near3 (IC (integrated adj circuit) \$6chip ASIC)) same (digital\$3 near3 cod\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 14:32
S35	1229	(counter same ((state mode status) near3 (IC (integrated adj circuit) \$6chip ASIC))) and @ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 09:45
S36	12	S35 and counter same (digital\$3 near3 cod\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 09:51
S37	0	S36 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7 record\$5 meter\$5) near3 (parameter near3 (IC (integrated adj circuit) \$6chip ASIC))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 09:53
S38	279	S35 and counter same digital\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 09:46

S39	0	S38 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7 record\$5 meter\$5) near3 (parameter near3 (IC (integrated adj circuit) \$6chip ASIC))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 09:47
S40	10	((parameter near3 (IC (integrated adj circuit) \$6chip ASIC)) same (digital\$3 near3 cod\$3)) and @ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 09:53
S41	78	S35 and counter same ((digital\$3 binary) near3 cod\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 09:52
S42	1	S41 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7 record\$5 meter\$5) near3 (parameter near3 (IC (integrated adj circuit) \$6chip ASIC))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 09:53
S43	0	S40 and ((state mode status) near3 (IC (integrated adj circuit) \$6chip ASIC))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 14:26
S44	85	S25 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7 record\$5 meter\$5) with (voltage near3 (change variation difference))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 10:28
S45	4	S44 and (((analysis analyzing analyzed analysing) adj2 (assembly unit system device apparatus machine mechanism section station means module set instrument tool circuit equipment cell)) analyzer analyser) near5 (IC (integrated adj circuit) \$6chip ASIC)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 10:38
S46	1229	(324/76.16,73.1.ccls.) and @ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 10:22

S47	4347	(324/763,765.ccls.) and @ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 10:22
S48	4544	(324/158.1.ccls.) and @ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 10:24
S49	3981	(714/724,726.ccls.) and @ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 10:25
S50	259	(702/127.ccls.) and @ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 10:26
S51	106	S46 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7 record\$5 meter\$5) with (voltage near3 (change variation difference))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 10:30
S52	435	S47 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7 record\$5 meter\$5) with (voltage near3 (change variation difference))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 10:31
S53	250	S48 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7 record\$5 meter\$5) with (voltage near3 (change variation difference))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 10:34
S54	93	S49 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7 record\$5 meter\$5) with (voltage near3 (change variation difference))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 10:36

S55	10	S50 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identif\$7 record\$5 meter\$5) with (voltage near\$3 (change variation difference))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 14:26
S56	5	S51 and (((analysis analyzing analyzed analysing) adj2 (assembly unit system device apparatus machine mechanism section station means module set instrument tool circuit equipment cell)) analyzer analyser) with (IC (integrated adj circuit) \$6chip ASIC)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 10:59
S57	19	S52 and (((analysis analyzing analyzed analysing) adj2 (assembly unit system device apparatus machine mechanism section station means module set instrument tool circuit equipment cell)) analyzer analyser) with (IC (integrated adj circuit) \$6chip ASIC)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 11:03
S58	5	S53 and (((analysis analyzing analyzed analysing) adj2 (assembly unit system device apparatus machine mechanism section station means module set instrument tool circuit equipment cell)) analyzer analyser) with (IC (integrated adj circuit) \$6chip ASIC)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 11:22
S59	2	S54 and (((analysis analyzing analyzed analysing) adj2 (assembly unit system device apparatus machine mechanism section station means module set instrument tool circuit equipment cell)) analyzer analyser) with (IC (integrated adj circuit) \$6chip ASIC)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 11:23
S60	0	S55 and (((analysis analyzing analyzed analysing) adj2 (assembly unit system device apparatus machine mechanism section station means module set instrument tool circuit equipment cell)) analyzer analyser) with (IC (integrated adj circuit) \$6chip ASIC)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 10:45
S61	17828	(check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identif\$7 record\$5 meter\$5) near\$3 (operat\$5 near\$1 parameter) and @ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/13 07:39
S62	210	S61 and (parameter near\$3 (IC (integrated adj circuit) \$6chip ASIC))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/13 08:57



S63	45	S62 and ((state mode status) near3 (IC (integrated adj circuit) \$6chip ASIC))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/13 08:59
S64	14	S63 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7 record\$5 meter\$5) with (voltage near3 (change variation difference))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/13 08:59
S65	1	S64 and counter same (parameter near3 (IC (integrated adj circuit) \$6chip ASIC))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 14:33
S66	176	S61 and ((operat\$5 near1 parameter) near3 (IC (integrated adj circuit) \$6chip ASIC))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 16:35
S67	32	S66 and ((state mode status) near3 (IC (integrated adj circuit) \$6chip ASIC))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 16:57
S68	6	S67 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7 record\$5 meter\$5) with (voltage near3 (change variation difference))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/12 16:58
S69	15941	(detect\$3 sens\$3 measur\$5 examin\$5 test\$3 determin\$3 inspect\$3 anal\$5 monitor\$3 identifi\$7 record\$5 meter\$5) near3 (operat\$5 near1 parameter) and @ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/13 09:48
S70	14815	(detect\$3 sens\$3 measur\$5 examin\$5 test\$3 determin\$3 inspect\$3 anal\$5 monitor\$3 identifi\$7 record\$5 meter\$5) near3 (operat\$5 adj1 parameter) and @ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/13 10:15

S71	5132	(assembly unit system device apparatus machine mechanism means module set instrument tool circuit equipment method) near3 (detect\$3 sens\$3 measur\$5 examin\$5 test\$3 determin\$3 inspect\$3 anal\$5 monitor\$3 identif\$7 record\$5 meter\$5) near3 (operat\$5 adj1 parameter) and @ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/13 08:55
S72	102	S71 and (operat\$5 adj1 parameter) near3 (IC (integrated adj circuit) \$6chip ASIC)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/13 08:57
S73	17	S72 and ((state mode status) near3 (IC (integrated adj circuit) \$6chip ASIC))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/13 09:49
S74	3	S73 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identif\$7 record\$5 meter\$5) with (voltage near3 (change variation difference))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/13 10:16
S75	632	(counter and (operating adj parameter) and (voltage near2 (change variation difference)) and (state mode status) and (IC (integrated adj circuit) \$6chip ASIC) and digital\$3) and @ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/13 10:25
S76	144	(detect\$3 sens\$3 measur\$5 examin\$5 test\$3 determin\$3 inspect\$3 anal\$5 monitor\$3 identif\$7 record\$5 meter\$5) near3 (operat\$5 near1 parameter) and S75	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/13 09:48
S77	44	S76 and ((state mode status) near3 (IC (integrated adj circuit) \$6chip ASIC))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/13 10:18
S78	2	("4,952,849").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/07/13 09:58

S79	7309	(detect\$3 sens\$3 measur\$5) near3 (operat\$5 adj1 parameter) and @ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/13 10:30
S80	31	S77 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7 record\$5 meter\$5) with (voltage near3 (change variation difference))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/13 10:26
S81	414	S79 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identifi\$7 record\$5 meter\$5) with (voltage near3 (change variation difference))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/13 10:31
S82	17	S81 and ((state mode status) near3 (IC (integrated adj circuit) \$6chip ASIC))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/13 10:33
S83	4	S82 and digital\$3 same counter	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/13 10:21
S84	0	((counter and (operating adj parameter) and (voltage near2 (change variation difference)) and (state mode status) and (IC (integrated adj circuit) \$6chip ASIC) and digital\$3).clm. ) and @ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/13 10:25
S85	1	S79 and ((state mode status) near3 (IC (integrated adj circuit) \$6chip ASIC)) same counter	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/13 10:34
S86	2541	measur\$5 near3 (operat\$5 adj1 parameter) and @ad<"20030810"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/13 10:30

S87	126	S86 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identif\$7 record\$5 meter\$5) with (voltage near\$3 (change variation difference))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/13 10:31
S88	8	S87 and (check\$3 detect\$3 sens\$3 measur\$5 comput\$3 calculat\$3 \$2valuat\$3 examin\$5 test\$3 determin\$3 recogniz\$3 inspect\$3 anal\$5 monitor\$3 diagnos\$3 identif\$7 record\$5 meter\$5 specif\$5) near\$3 ((state mode status) near\$3 (IC (integrated adj circuit) \$6chip ASIC))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/13 10:36
S89	17	S87 and (state mode status) same counter	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/13 10:35
S90	4	S88 and (state mode status) same counter	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/07/13 10:35